	Application No.	Applicant(s)	
A1 /*	10/815,418	FILIPPI ET AL.	
Notice of Allowability	Examiner	Art Unit	
	DUNG A. LE	2818	
The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RI of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in this apport or other appropriate communication GHTS. This application is subject to and MPEP 1308.	olication. If not includ will be mailed in due	led course. <b>THIS</b>
1. This communication is responsive to Election dated 7/21 co	omunication on 8/31/2005.		
2. X The allowed claim(s) is/are <u>1-3,5-10 and 12-15</u> .			
3.  Acknowledgment is made of a claim for foreign priority un a)	been received.  been received in Application No cuments have been received in this received in the catalogue of the submitted.  The submitted is a comment or in the Comment or in the Comment of the catalogue of the received in the catalogue of the received in the catalogue of the catalo	complying with the re S AMENDMENT or Nation is deficient.  948) attached  Office action of the land in the front (not the land).  nust be submitted.	quirements NOTICE OF
Attachment(s)  1. ☐ Notice of References Cited (PTO-892)  2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)  3. ☑ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date  4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	5. Notice of Informal P 6. Interview Summary Paper No /Mail Dat 8), 7. Examiner's Amendn 8. Examiner's Stateme	(PTO-413), e nent/Comment	
or biological material	9.	DUNGL	
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## **DETAILED ACTION**

## Oath/Declaration

The oath/declaration filed on 4/1/2004 is acceptable.

## **Information Disclosure Statement**

This office acknowledges of the following items from the Applicant:

Information Disclosure Statement (IDS) filed on 4/1/2004 and made of record.

The references cited on the PTOL 1449 form have been considered.

# Specification

The specification has been checked to the extent necessary to determine the presence of all possible minor errors. However, the applicant's cooperation is requested in correcting any errors of which applicant may become aware in the specification.

### Examiner's Amendment.

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

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Authorization for this examiner's amendment was given in a telephone interview with Attorney J. Bitetto on 8/31/2005. The Applicants have been amended as follows:

Cancel Claims 4, 11 and 16-30.

In claim 1, change "determining strain at a location in structure;" to -- determining strain at a location in structure including determining strain at the bottom of a via in contact with a liner in the via; --

In claim 10, change "correlating the strain threshold to characteristics of the metal structure; and

predicting reliability of semiconductor chips based upon measured characteristics of the metal structure." to -- correlating the strain threshold to characteristics of the metal structure, wherein the characteristics of the metal structure include a liner thickness formed in via holes; and

predicting reliability of semiconductor chips based upon measured characteristics of the metal structure including measuring a thickness of a liner to predict electrical failures.--

### Reason for allowance

Claims 1-3, 5- 10 and 12- 15 are allowed. The following is an examiner's statement of reason for allowance:

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Set of Claims 1-3 and 5-9 are allowed: none of the references of record teaches or suggests the claimed Method for evaluating reliability of a semiconductor chip having the step of determining strain at a location in structure including determining strain at the bottom of a via in contact with a liner in the via and among other steps/limitations as claimed in independent claim 1.

Set of Claims 10, 12- 15 are allowed: none of the references of record teaches or suggests the claimed Method for evaluating reliability of a semiconductor chip (in addition to other steps as claimed in independent claim 10) comprising: the step of correlating the strain threshold to characteristics of the metal structure, wherein the characteristics of the metal structure include a liner thickness formed in via holes and predicting reliability of semiconductor chips based upon measured characteristics of the metal structure including measuring a thickness of a liner to predict electrical failures.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance".

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### Conclusion

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Dung A. Le whose telephone number is (571) 272-1784. The examiner can normally be reached on Monday-Tuesday and Thursday 6:00am- 4:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Nelms can be reached on (571) 272-1787. The central fax phone numbers for the organization where this application or proceeding is assigned are (571)272-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

DUNG A. LE DU Primary Examiner Art Unit 2818